

**Search Notes**

Application/Control No.

09/116,124

Examiner

Hai Tran

Applicant(s)/Patent under  
Reexamination

NISHINA ET AL.

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
update previous search			
		4/28/05	HUT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR